

Serial No. n/a


R E M A R K S

Claims 1-6 have been amended to remove the reference numerals and conform with U.S. practice. Claims 7 and 8 have been added to include features which were previously included in a vague manner in claims 6 and 1, respectively.

Entry of the Amendment is respectfully requested and in order.

Respectfully submitted,

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MARKED-UP VERSION SHOWING CHANGES:

1. (amended) Measuring probe [(100, 200, 300)] for measuring high frequencies, [having] comprising a contact end [(20)] for contacting planar structures and a co-axial cable end [(18)] for connection to a co-axial cable [(22),] ; a co-planar conductor structure [(10)] having at least two conductors [(12, 14) being] arranged between the contact end [(20)] and the co-axial cable end ; [(18) and] a dielectric [(28) acting as a mounting for] for mounting the co-planar conductor structure [(10)], the dielectric being arranged on the co-planar conductor structure [(10), characterised in that] ; the dielectric [(28) is] being arranged on at least one side[, and in particular on both sides,] of the co-planar conductor structure [(10)] in a central section between, and spaced, [away from] in the direction of propagation, from the co-axial cable end [(19)] and the contact end [(20)], [in such a way that] each conductor [(12, 14)] in the co-planar conductor structure [(10) is] being formed to be individually free in space and resilient in relation to the dielectric [(28) acting as its mounting], 'a respective gap [(16)] being formed between each pair of conductors [(12, 14)] in the co-planar conductor structure [(10)] from the co-axial cable end [(18)] to the contact end [(20)] in such a way that a constant characteristic impedance is obtained from the co-axial cable end [(18)] to the contact end [(20)].

2. (amended) Measuring probe [(100, 200, 300)] according to claim 1, [characterised in that] wherein the respective gap [(16)] is [made] wider in the region of the dielectric [(28)] than in the region of the co-planar conductor structure [(10)] where there is no dielectric [(28)].

3. (amended) Measuring probe [(100, 200, 300)] according to

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claim 1, [characterised in that] wherein the dielectric [is in the form of] includes at least one block of quartz [(28)].

4. (amended) Measuring probe [(100, 200, 300)] according to claim 1, [characterised in that] wherein the dielectric [(28)] has, on a side where it is connected to the co-planar conductor structure [(10)], a metal coating [which] having substantially [coincides in] the same shape [with] as the [latter] co-planar conductor structure.

5. (amended) Measuring probe [(200)] according to claim 1, [characterised in that] wherein the dielectric [(28)] is metallised over its full area on a side remote from the co-planar conductor structure.

6. (amended) Measuring probe according to claim 1, [characterised in that] further including a planar circuit [and in particular an electrical or electronic, i.e. active, circuit or at least one active circuit element is] arranged at the co-axial cable end [(18)].